



C O N E X A N T TM

Advanced Packaging of Image Sensors

Usama Abdali

Newport Beach, CA

Image Sensors: the heart of digital cameras



Images taken with Conexant
SXGA (1280 × 1024)
1.3 megapixel image sensor

- **Special requirements for image sensor packaging**
- **Traditional packaging for digital still cameras**
- **Additional requirements for wireless handset camera modules**
- **Case #1: Encapsulated package**
- **Case #2: Chip scale package**

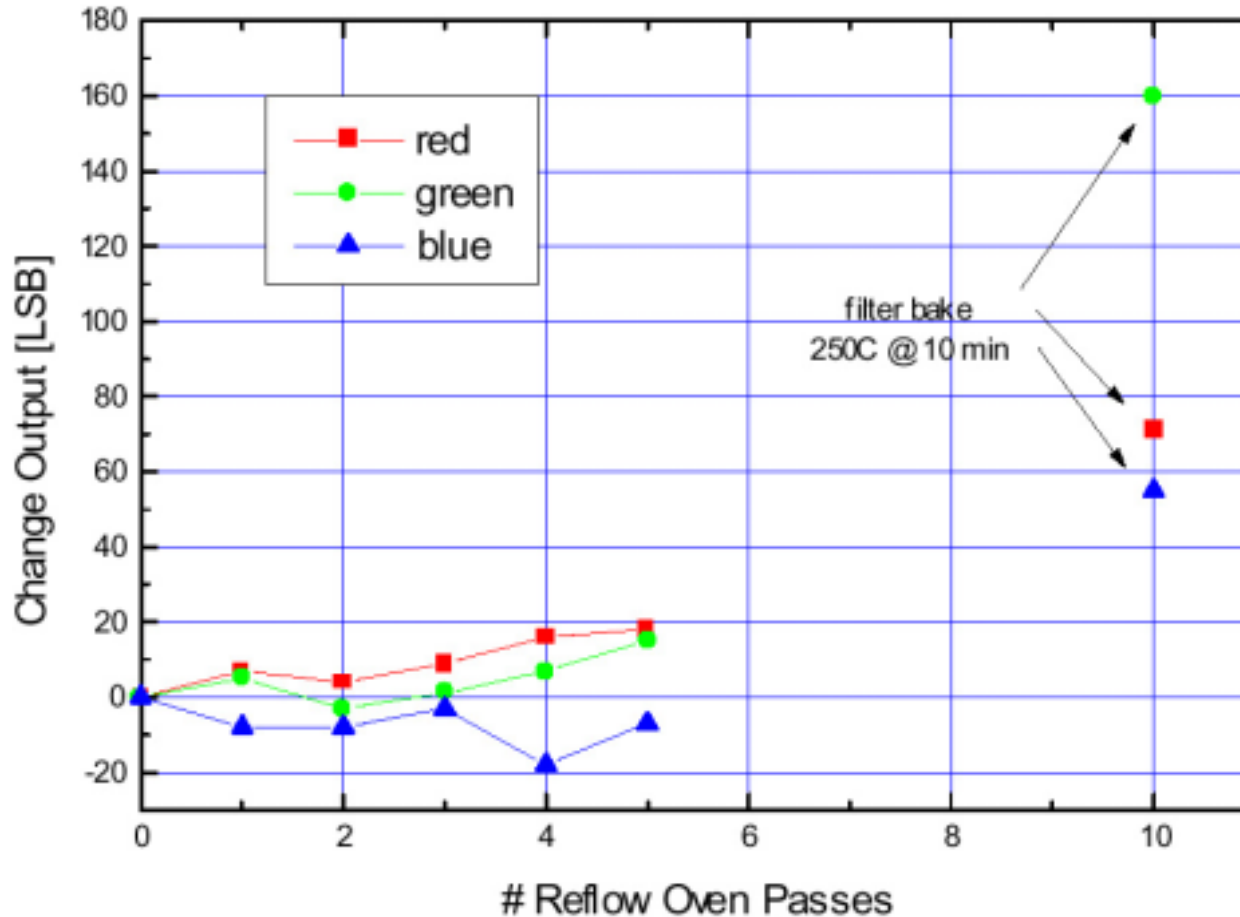
Special packaging requirements



- Limited process temperatures
- Optically transparent material
- Contamination control during packaging
- Alignment of image sensor package to optics mechanism
- Package Test

- **Two types of color filter materials:**
- **Organic dyes**
 - Maximum process temperatures can be limited to 150°C or lower
 - May require low temperature die attach process and low temperature wirebonding
 - Might not be solder reflow compatible
- **Pigments**
 - Allows higher process temperatures
 - Can be solder reflow compatible
- **Microlens materials can also be affected by temperature**

Effect of temperature on color filters



After 250°C bake

Red: -9%

Green: -24%

Blue: -8%

Red - Cyan

Green - Magenta

Blue - Yellow

Optically transparent materials

- **Choices are limited:**
- **Glass**
 - 98-99% transmittance of visible light
 - expensive
 - difficult to handle
- **Clear Organics**
 - 90-92% transmittance of visible light
 - susceptible to degradation
 - large thermal expansion mismatch with die

Optically transparent materials, cont.

Glass lid



Organic
- after 3
passes of
solder reflow



- **VGA-format image sensors contain over 300,000 pixels**
- **Typical pixel sizes range from 5-10 μm and are shrinking**
- **Contamination on die surface can be visible in image**
- **May be possible to correct for bad pixels in software**
- **Contamination far from the die surface is not in focus**

Alignment of sensor to optics

- **Wide range of techniques for image sensor-optics alignment:**
- **Low end “toy” digital cameras: simple assembly with no real alignment**
- **High-end digital cameras: precision active alignment, e.g. 6-axis robotic alignment fixtures**
- **Middle ground: passive alignment of image sensor and optics to the same datum features**

- Cannot contact surface of package above the active area of the image sensor, but must make reliable contact
- Must integrate a well-characterized and well-calibrated light source into the test handler (e.g. Tungsten-Halogen 3200°K)
- Must maintain flatness and parallelism if testing with optics

Traditional Imager Packaging Approach

- Ceramic or Plastic cavity package (LCC) with glass lid
- Package cost is high based on number of I/O
- LCC form factor is too large and expensive for embedding into wireless handsets



Wireless handset camera module



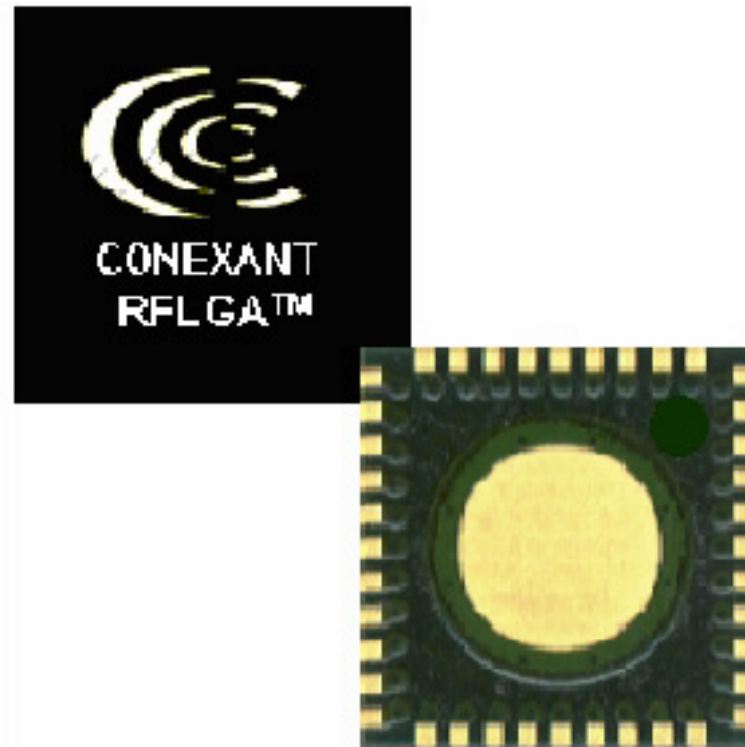
- Customer requirements:
- CIF or VGA format image sensor; both still and video imaging
- Integrated optics assembly and image-processing ASIC
- 2.7V power supply; power consumption < 100 milliwatts
- Complete module occupies < 1 cc
- Total price for sensor, package, optics, and ASIC < \$10
- Low Z-height is one of the most critical parameters for wireless handsets manufacturers

EETimes 9/8/00

Case #1: Encapsulated Imager Package



- Modeled on Conexant's Radio Frequency Land Grid Array Overmolded Package (used for transceivers)

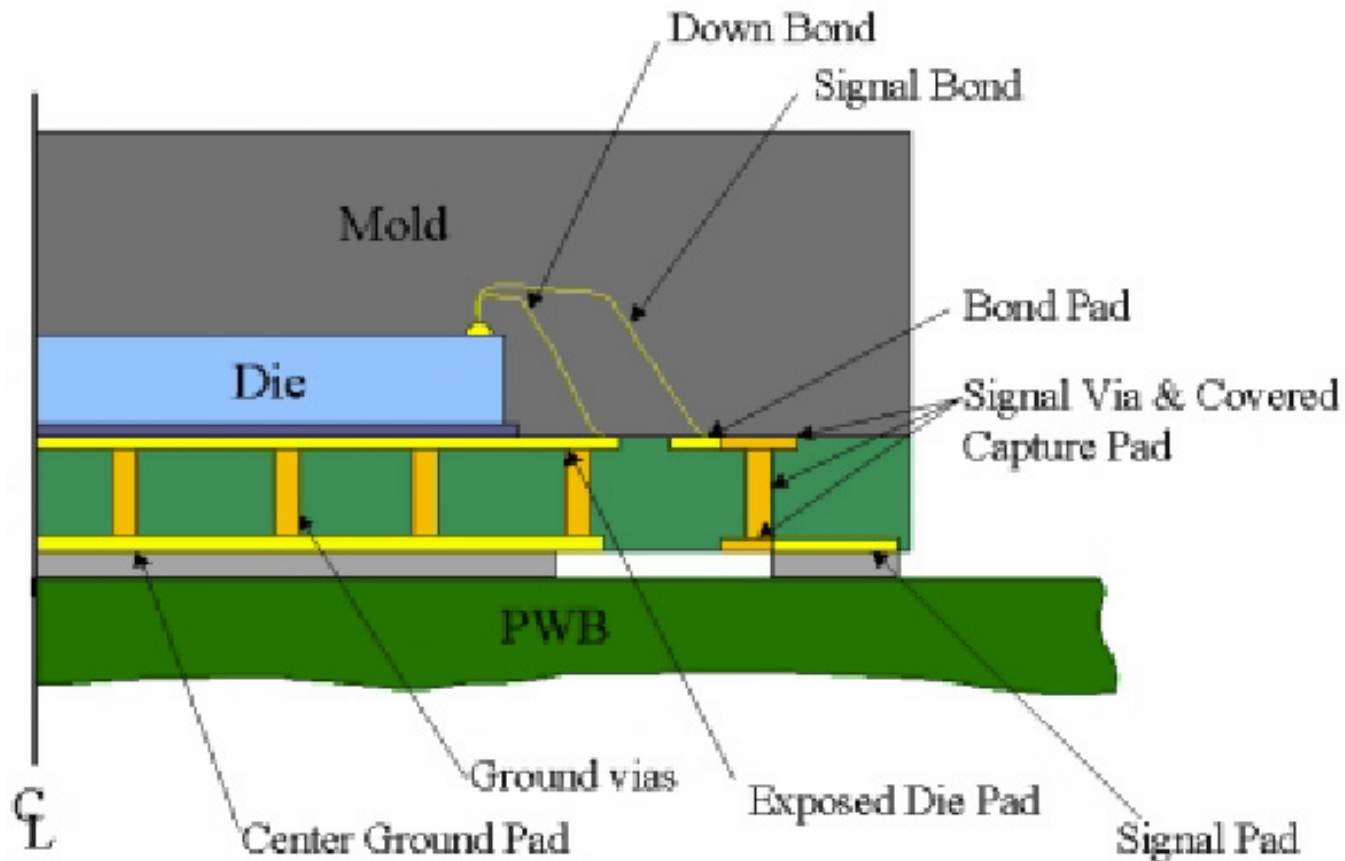


Advantages:

- In-house assembly and test capability
- Low cost, high volume product
- Thin form factor

Top and bottom view of a 6x6, 40 pin RFLGA.

Optical Land Grid Array Package



Half-symmetric representation of a typical RFLGA cross section.

- Replace overmold with dam-and-fill (clear encapsulant)

Optical LGA Process Flow



- Wafer Saw
- Die Attach to laminate substrate
- Plasma Clean
- Wire Bond
- Dam and Fill - *Dispensing or Printing**
- Branding*
- Saw Singulation of matrix*
- Electrical and optical testing*

** new process development required*

Transmission through encapsulant

- Clear encapsulant material transmits 90-92% of visible light
- Solder reflow had minimal impact on image quality



Glass lid

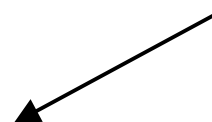
Encapsulated
- after 3
passes of
solder reflow



Optical Characterization

| Optical LGA | | | CLCC | | |
|------------------------------|----------|--------|------------------------------|-----------|--------|
| Sensitivity (counts/lux.sec) | | | Sensitivity (counts/lux.sec) | | |
| Channel | | | Channel | | |
| Red | Green | Blue | Red | Green | Blue |
| 22.15 | 26.04 | 22.57 | 28.77 | 34.81 | 31.71 |
| PRNU @ 1.2lux(%) | | | PRNU @ 1.2lux(%) | | |
| Channel | | | Channel | | |
| Red | Green | Blue | Red | Green | Blue |
| 2.47 | 1.92 | 3.3 | 1.65 | 1.39 | 1.52 |
| Noise | | | Noise | | |
| PTN | 0.238845 | counts | PTN | 0.1656567 | counts |
| PFPN | 0.998999 | counts | PFPN | 1.3694735 | counts |
| CFPN | 52.99283 | counts | CFPN | 52.892271 | counts |
| RFPN | 0.154281 | counts | RFPN | 0.1109943 | counts |
| RTN | 0.016778 | counts | RTN | 0.0190503 | counts |
| CTN | 0.014118 | counts | CTN | 0.0100404 | counts |

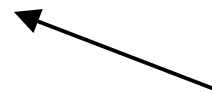
Photosensitivity in red, green, & blue channels



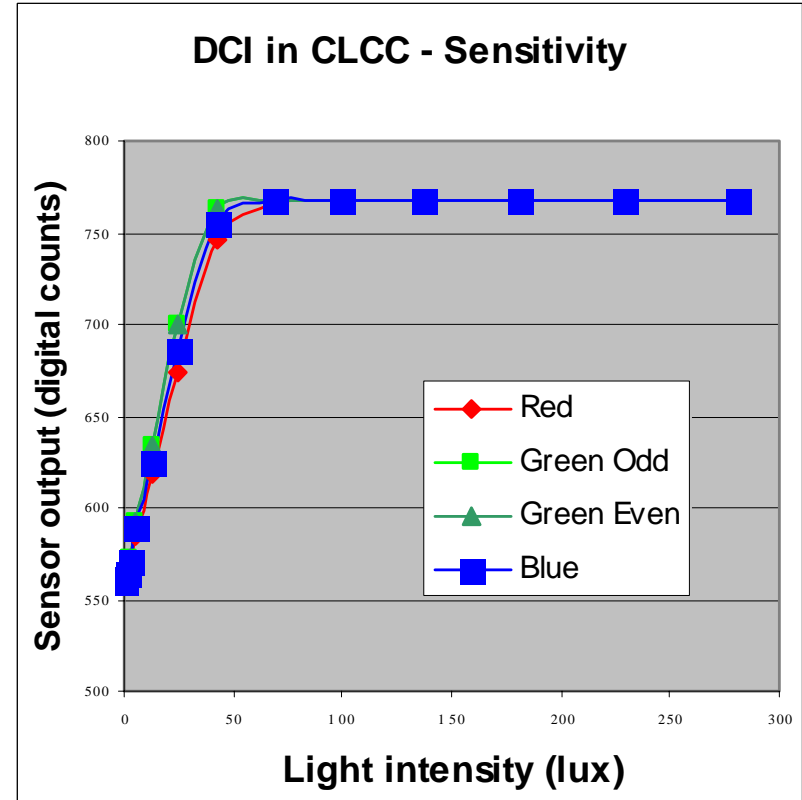
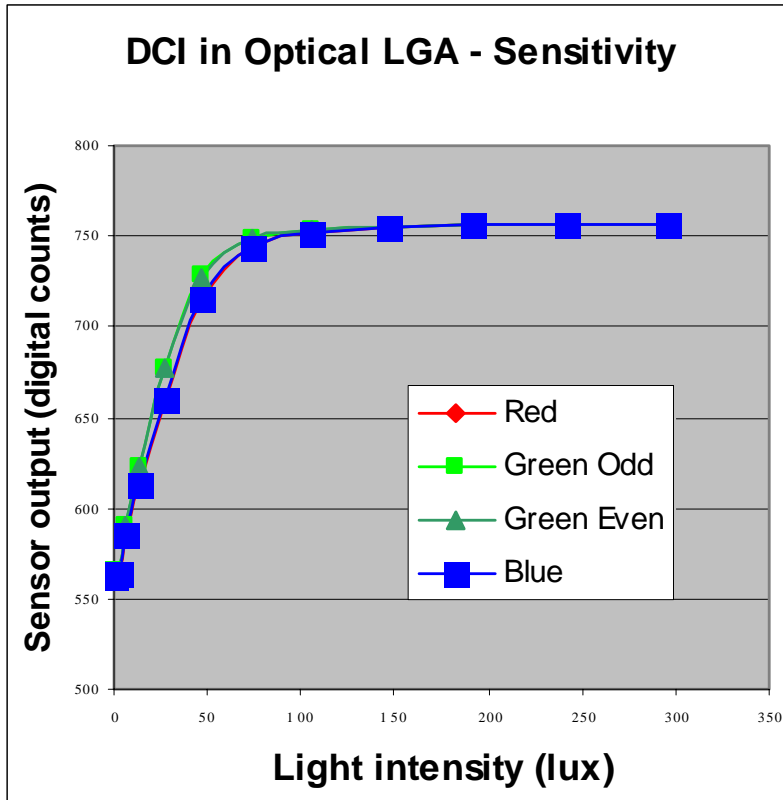
Pixel Response Non-Uniformity in flat field (no lens)



Noise (measured "in the dark")



Optical Characterization, cont.



The Optical LGA and CLCC had similar sensitivity, pixel response non-uniformity, and noise values.

Optical LGA Reliability



- JEDEC Level 4 Preconditioning
- 85°C / 85% RH
- Thermal Cycling
- 125°C High Temperature Storage
- 10,000 Lux Light Exposure

- Failures seen after 85/85 and thermal cycling

- C-SAM shows delamination of encapsulant from substrate due to CTE mismatch

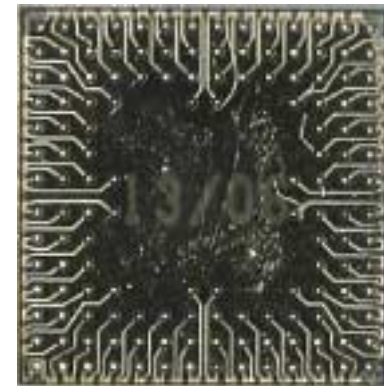
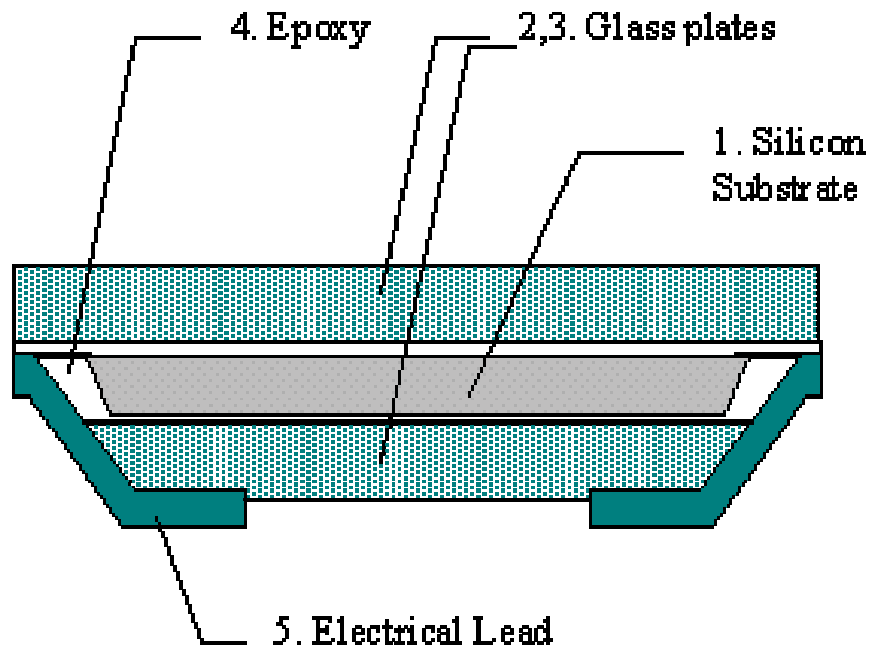
Optical LGA Feasibility Summary



- **Optical Performance & Characterization**
 - Preliminary results show comparable performance between Optical LGA package and CLCC
- **Package Reliability**
 - Package delamination failures seen - due to CTE mismatch between clear encapsulant and substrate
- **Future Work**
 - Investigate alternate clear encapsulant materials with lower CTE

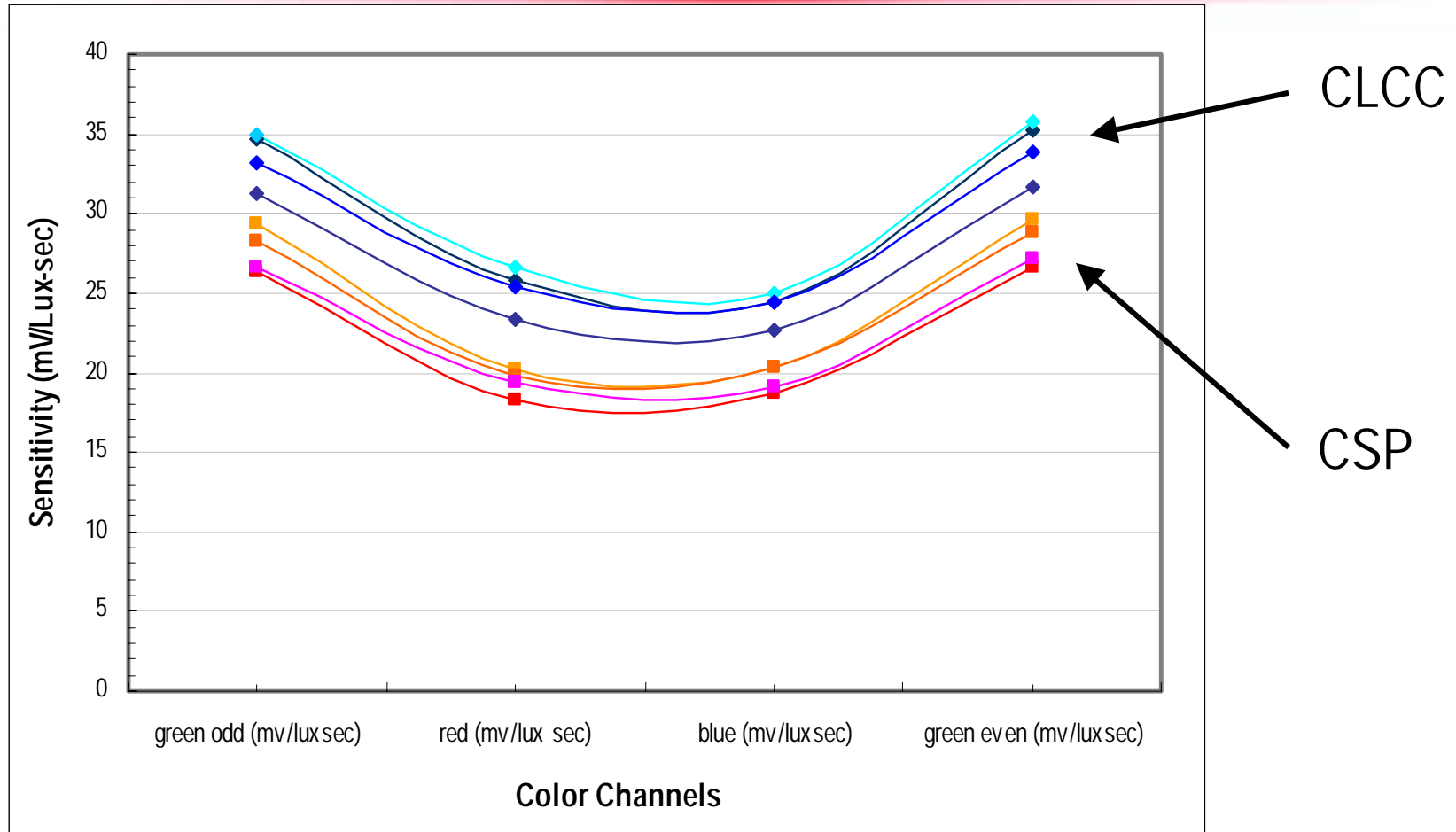
Case #2: Chip Scale Imager Package

- Wafer-level CSP
- Smaller, thinner, and lower cost than Optical LGA



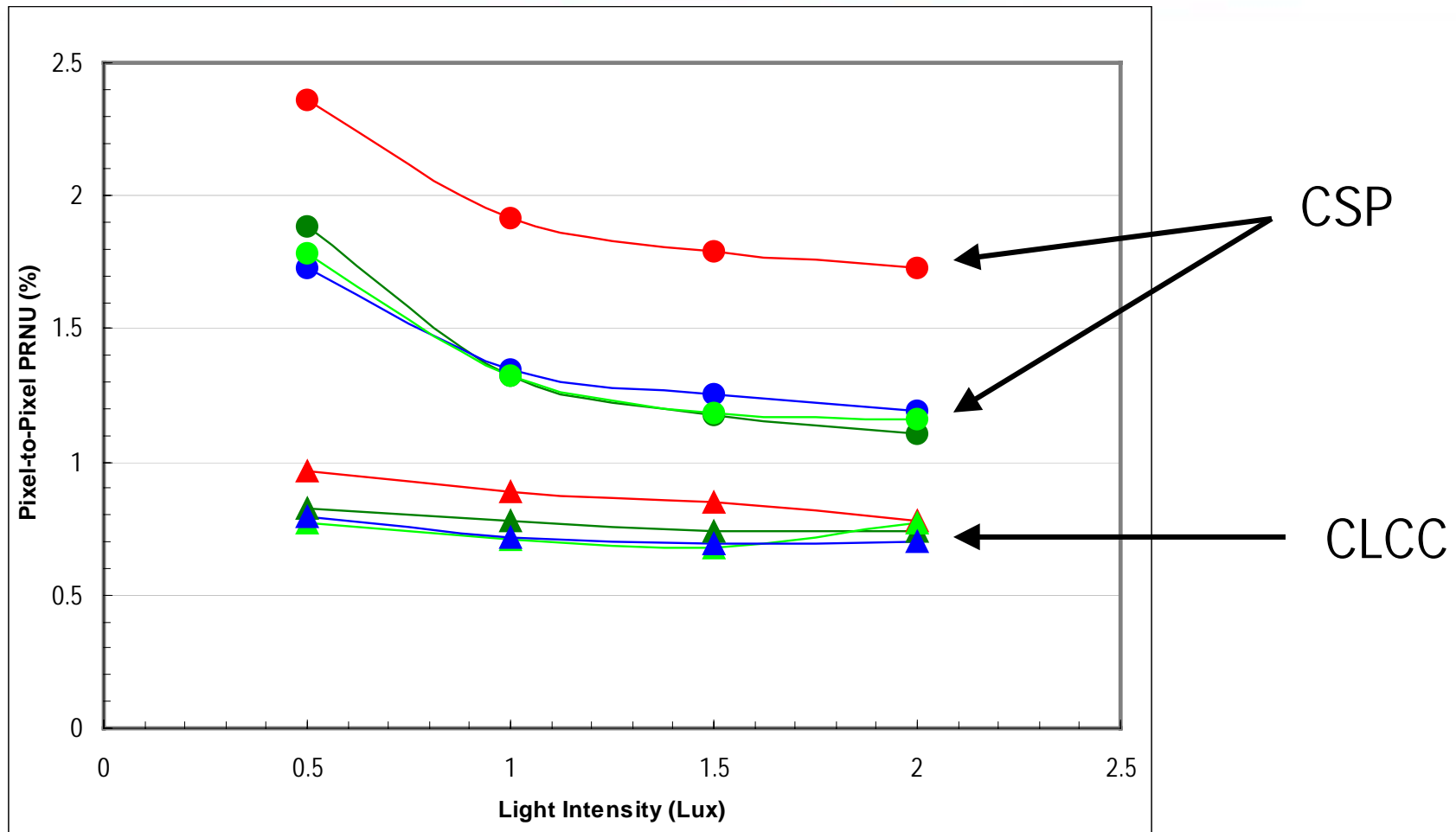
- **Compared CSP to CLCC performance with Conexant SXGA die**
 - Photosensitivity in R, G, and B
 - Pixel Response Non-Uniformity
 - Noise
 - Power Consumption
- **Expect that construction of CSP will reduce benefit of microlenses (no air gap - smaller Δ in refractive index)**
- **Maximum benefit of microlens in this system is 2X**

Photosensitivity



- **CSP has 15-20% less sensitivity than CLCC**
- **Red and Blue responses lower than Green for both packages**

Pixel Response Non-Uniformity



- CSP has higher PRNU, but within acceptable range
- Higher Red PRNU due to higher cross-talk

Noise and Power Consumption



- No distinct difference between CLCC and CSP in column fixed pattern noise and pixel fixed pattern noise
- No difference in power consumption

- Because of limited sample size, concentrated on temperature cycling and 85/85
- JEDEC Level 4 Preconditioning
- 85°C / 85% RH
- Thermal Cycling
- No failures seen

CSP Imager Package Summary



- Performance is similar to CLCC package, except for some degradation in photosensitivity
- Preliminary reliability results encouraging, need more thorough evaluation
- Challenges: automated test of small, thin imager sensor package